

<b>Notic of R ferenc s Cited</b>	Application/Control No. 10/047,528	Applicant(s)/Patent Under Reexamination KITAGAWA ET AL.	
	Examiner David Y. Chung	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,404,469	06-2002	Kitagawa et al.	349/96
	B	US-6,252,640	06-2001	Kim et al.	349/96
	C	US-6,245,399	06-2001	Sahouani et al.	428/1.31
	D	US-6,049,428	04-2000	Khan et al.	359/491
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000321426 A	11-2000	Japan	KITAGAWA et al.	G02B 05/30
	O	EP 881509 A2	12-1998	European Patent	KAMEYAMA et al.	G02B 05/30
	P	EP 881510 A2	12-1998	European Patent	MOTOMURA et al.	G02B 05/30
	Q	EP 908745 A1	04-1999	European Patent	KAMEYAMA et al.	G02B 05/30
	R	EP 940705 A1	09-1999	European Patent	KAMEYAMA et al.	G02F 01/1335
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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